

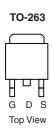
# IRF9620SPBF-VB Datasheet P-Channel 200V (D-S)MOSFET

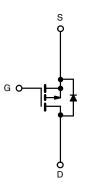
PRODUCT SUMMARY				
V <sub>DS</sub> (V)	-200			
R <sub>DS(on)</sub> (Ω)	V <sub>GS</sub> = -10 V	0.50		
Q <sub>g</sub> max. (nC)	44			
Q <sub>gs</sub> (nC)	7.1			
Q <sub>gd</sub> (nC)	27			
Configuration	Single			

#### **FEATURES**

- Dynamic dV/dt rating
- Repetitive avalanche rated
- P-channel
- · Fast switching
- Ease of paralleling
- Simple drive requirements







P-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATINGS</b> (T <sub>C</sub> = 25 °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V <sub>DS</sub>	-200	V	
Gate-Source Voltage			V <sub>GS</sub>	± 20	V	
Continuous Drain Current	V <sub>GS</sub> at -10 V	$T_{\rm C} = 25  ^{\circ}{\rm C}$ $T_{\rm C} = 100  ^{\circ}{\rm C}$	- I <sub>D</sub>	-11		
		T <sub>C</sub> = 100 °C		-6.8	Α	
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	-44		
Linear Derating Factor				1.0	W/°C	
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	700	mJ	
Repetitive Avalanche Current a			I <sub>AR</sub>	-11	Α	
Repetitive Avalanche Energy <sup>a</sup>			E <sub>AR</sub>	13	mJ	
Maximum Power Dissipation	$T_C = 2$	25 °C	P <sub>D</sub>	125	W	
Peak Diode Recovery dV/dt <sup>c</sup>			dV/dt	-5.0	V/ns	
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C	
Soldering Recommendations (Peak temperature) <sup>d</sup>	for 10 s			300	7	
Mounting Toyaus	6-32 or M3 screw			10	lbf ⋅ in	
Mounting Torque				1.1	N⋅m	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b.  $V_{DD}=$  -50 V, starting  $T_J=25$  °C, L = 8.7 mH,  $R_g=25$   $\Omega$ ,  $I_{AS}=$  -11 A (see fig. 12). c.  $I_{SD}\leq$  -11 A, dl/dt  $\leq$  150 A/µs,  $V_{DD}\leq$   $V_{DS}$ ,  $V_{DS}$ 0 °C.

- d. 1.6 mm from case.



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	62		
Case-to-Sink, Flat, Greased Surface	R <sub>thCS</sub>	0.50	-	°C/W	
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	1.0		

PARAMETER	SYMBOL	TES	TEST CONDITIONS			MAX.	UNIT
Static				Į.	!	!	
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> =	-200	-	-	V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	Reference to 25 °C, I <sub>D</sub> = -1 mA		-0.2	-	V/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =	V <sub>GS</sub> , I <sub>D</sub> = -250 μA	-2.0	-	-4.0	V
Gate-Source Leakage	I <sub>GSS</sub>	,	V <sub>GS</sub> = ± 20 V		-	± 100	nA
7 Oals Walless Buds O and		V <sub>DS</sub> =	$V_{DS} = -200 \text{ V}, V_{GS} = 0 \text{ V}$		-	-100	μΑ
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = -160 \	V <sub>DS</sub> = -160 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C		-	-500	
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = -10 V	I <sub>D</sub> = -6.6 A <sup>b</sup>	-	0.50	-	Ω
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub> =	-50 V, I <sub>D</sub> = -6.6 A <sup>b</sup>	4.1	-	-	S
Dynamic		•			•	•	
Input Capacitance	C <sub>iss</sub>	$V_{GS} = 0 V$		-	1200	-	pF
Output Capacitance	C <sub>oss</sub>		$V_{DS} = -25 \text{ V},$		370	-	
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1.0 MHz, see fig. 5		-	81	-	
Total Gate Charge	Qg		I <sub>D</sub> = -11 A, V <sub>DS</sub> = -160 V, see fig. 6 and 13 <sup>b</sup>	-	-	44	nC
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = -10 V		-	-	7.1	
Gate-Drain Charge	Q <sub>gd</sub>			-	-	27	
Turn-On Delay Time	t <sub>d(on)</sub>		•	-	14	-	
Rise Time	t <sub>r</sub>	V <sub>DD</sub> =	V <sub>DD</sub> = -100 V, I <sub>D</sub> = -11 A		43	-	- ns
Turn-Off Delay Time	t <sub>d(off)</sub>	$R_g = 9.1 \Omega$ , $R_D = 8.6 \Omega$ , see fig. 10 b		-	39	-	
Fall Time	t <sub>f</sub>			-	38	-	
Internal Drain Inductance	L <sub>D</sub>	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	- nH
Internal Source Inductance	L <sub>S</sub>			-	7.5	-	
Gate Input Resistance	$R_g$	f = 1 MHz, open drain		0.3	-	1.7	Ω
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET sym showing the	MOSFET symbol showing the		-	-11	
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>	integral reverse p -n junction diode		-	-	-44	A
Body Diode Voltage	V <sub>SD</sub>	$T_J = 25$ °C, $I_S = -11$ A, $V_{GS} = 0$ V b		-	-	-5	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	T <sub>J</sub> = 25 °C, I <sub>F</sub> = -11 A, dI/dt = 100 A/μs b		-	250	300	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			-	2.9	3.6	μC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S$ and $L_D$ )				L <sub>D</sub> )	

#### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width  $\leq$  300  $\mu s$ ; duty cycle  $\leq$  2 %.



### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

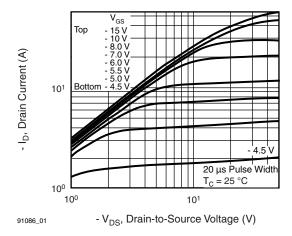


Fig. 1 - Typical Output Characteristics, T<sub>C</sub> = 25 °C

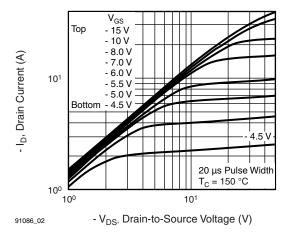


Fig. 2 - Typical Output Characteristics,  $T_C = 150$  °C

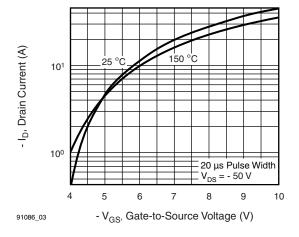


Fig. 3 - Typical Transfer Characteristics

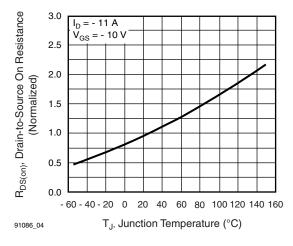


Fig. 4 - Normalized On-Resistance vs. Temperature

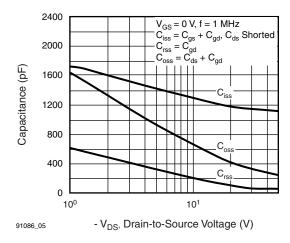


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

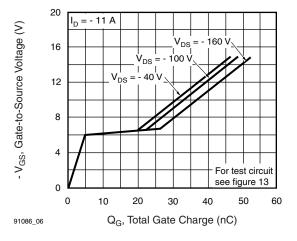


Fig. 6 - Typical Gate Charge vs. Drain-to-Source Voltage



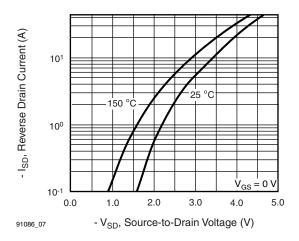


Fig. 7 - Typical Source-Drain Diode Forward Voltage

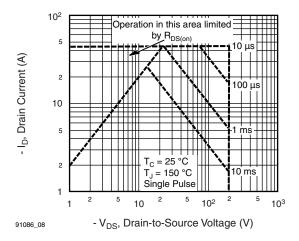


Fig. 8 - Maximum Safe Operating Area

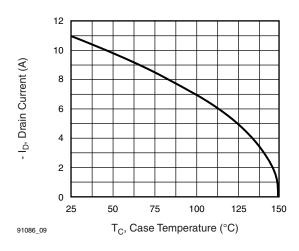


Fig. 9 - Maximum Drain Current vs. Case Temperature

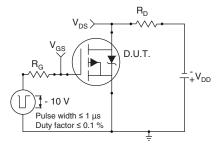


Fig. 10a - Switching Time Test Circuit

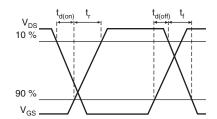


Fig. 10b - Switching Time Waveforms

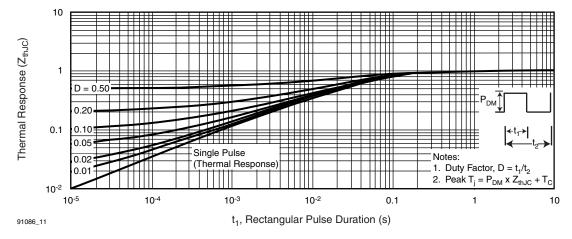


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



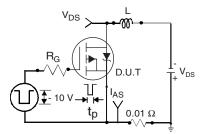


Fig. 12a - Unclamped Inductive Test Circuit

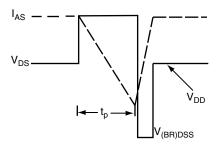


Fig. 12b - Unclamped Inductive Waveforms

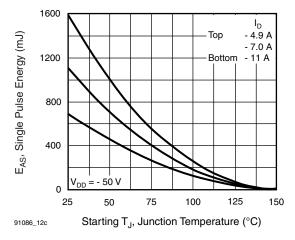


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

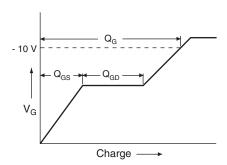


Fig. 13a - Basic Gate Charge Waveform

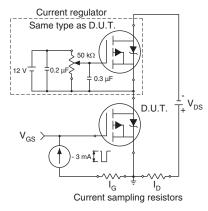
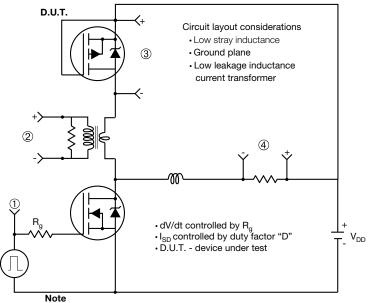


Fig. 13b - Gate Charge Test Circuit



#### Peak Diode Recovery dV/dt Test Circuit



• Compliment N-Channel of D.U.T. for driver

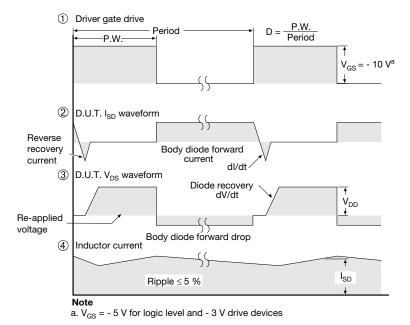
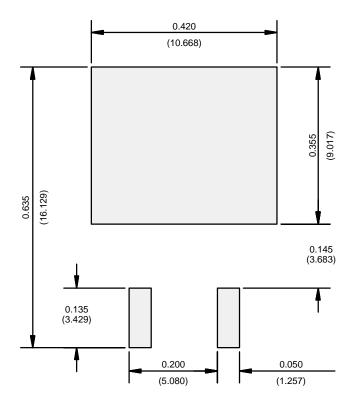


Fig. 14 - For P-Channel



### RECOMMENDED MINIMUM PADS FOR D<sup>2</sup>PAK: 3-Lead



Recommended Minimum Pads Dimensions in Inches/(mm)



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